

TRIACs, 25A

Snubberless and Standard

FEATURES

- High current triac
- Low thermal resistance with clip bonding
- Low thermal resistance insulation ceramic for insulated TO-220AB & TO-3P package
- High commutation (4 quadrant) or very High commutation (3 quadrant) capability
- 26T series are **UL** certified (File ref: E320098)
- Packages are RoHS compliant

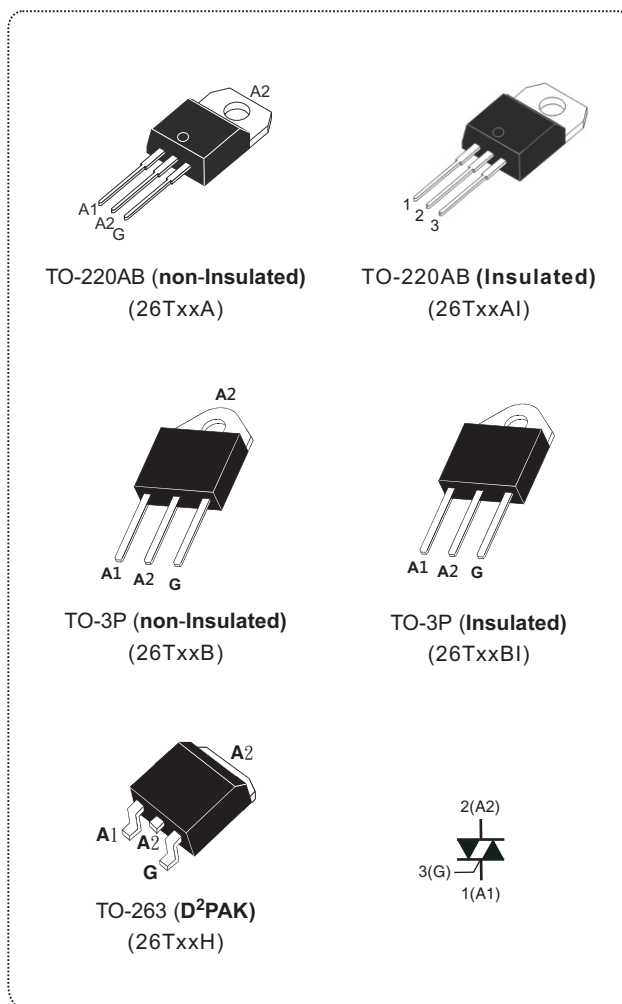
APPLICATIONS

Applications include the ON/OFF function in applications such as static relays, heating regulation, induction motor starting circuits, etc., or for phase control operation in light dimmers, motor speed controllers, and similar.

The snubberless versions are especially recommended for use on inductive loads, due to their high commutation performances. The 26T series provides an insulated tab (rated at 2500V_{RMS}).

MAIN FEATURES

SYMBOL	VALUE	UNIT
$I_{T(RMS)}$	25	A
V_{DRM}/V_{RRM}	600 to 1200	V
$I_{GT(Q1)}$	35 to 50	mA



ABSOLUTE MAXIMUM RATINGS					
PARAMETER	SYMBOL	TEST CONDITIONS		VALUE	UNIT
RMS on-state current (full sine wave)	$I_{T(RMS)}$	TO-3P	$T_c = 105^\circ\text{C}$	25	A
		TO-263/TO-220AB/TO-3P insulated	$T_c = 100^\circ\text{C}$		
		TO-220AB insulated	$T_c = 75^\circ\text{C}$		
Non repetitive surge peak on-state current (full cycle, T_j initial = 25°C)	I_{TSM}	F = 50 Hz	t = 20 ms	250	A
		F = 60 Hz	t = 16.7 ms	260	
I^2t Value for fusing	I^2t	$t_p = 10$ ms		340	A ² s
Critical rate of rise of on-state current $I_G = 2I_{GT}$, $t_i \leq 100$ ns	di/dt	F = 100 Hz	$T_j = 125^\circ\text{C}$	50	A/ μ s
Peak gate current	I_{GM}	$T_p = 20$ μ s	$T_j = 125^\circ\text{C}$	4	A
Average gate power dissipation	$P_{G(AV)}$	$T_j = 125^\circ\text{C}$		1	W
Storage temperature range	T_{stg}			- 40 to + 150	$^\circ\text{C}$
Operating junction temperature range	T_j			- 40 to + 125	

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SNUBBERLESS and Logic level (3 quadrants)						
SYMBOL	TEST CONDITIONS	QUADRANT		26Txxxx		Unit
				CW	BW	
$I_{GT}^{(1)}$	$V_D = 12\text{ V}, R_L = 30\Omega$	I - II - III	MAX.	35	50	mA
V_{GT}		I - II - III		1.3		V
V_{GD}	$V_D = V_{DRM}, R_L = 3.3K\Omega$ $T_J = 125^\circ\text{C}$	I - II - III	MIN.	0.2		V
$I_H^{(2)}$	$I_T = 500\text{ mA}$		MAX.	50	75	mA
I_L	$I_G = 1.2 I_{GT}$	I - III	MAX.	70	80	mA
		II		80	100	
$dV/dt^{(2)}$	$V_D = 67\% V_{DRM}$, gate open, $T_J = 125^\circ\text{C}$		MIN.	500	1000	V/ μs
$(dI/dt)_C^{(2)}$	Without snubber, $T_J = 125^\circ\text{C}$			13	22	A/ms

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Standard (4 quadrants)					
SYMBOL	TEST CONDITIONS	QUADRANT		26Txxxx	UNIT
				B	
$I_{GT}^{(1)}$	$V_D = 12\text{ V}, R_L = 30\Omega$	I - II - III	MAX.	50	mA
V_{GT}		IV		100	
V_{GD}	$V_D = V_{DRM}, R_L = 3.3K\Omega, T_J = 125^\circ\text{C}$	ALL		1.3	V
V_{GD}	$V_D = V_{DRM}, R_L = 3.3K\Omega, T_J = 125^\circ\text{C}$	ALL		0.2	V
$I_H^{(2)}$	$I_T = 500\text{ mA}$		MAX.	80	mA
I_L	$I_G = 1.2 I_{GT}$	I - III - IV	MAX.	70	mA
		II		160	
$dV/dt^{(2)}$	$V_D = 67\% V_{DRM}$, gate open, $T_J = 125^\circ\text{C}$		MIN.	500	V/ μs
$(dV/dt)_C^{(2)}$	$(dI/dt)_C = 13.3\text{ A/ms}, T_J = 125^\circ\text{C}$		MIN.	10	V/ μs

STATIC CHARACTERISTICS					
SYMBOL	TEST CONDITIONS			VALUE	UNIT
$V_{TM}^{(2)}$	$I_{TM} = 35\text{ A}, t_P = 380\text{ }\mu\text{s}$	$T_J = 25^\circ\text{C}$	MAX.	1.55	V
$V_{th}^{(2)}$	Threshold voltage	$T_J = 125^\circ\text{C}$	MAX.	0.85	V
$R_d^{(2)}$	Dynamic resistance	$T_J = 125^\circ\text{C}$	MAX.	16	m Ω
I_{DRM} I_{RRM}	$V_D = V_{DRM}$ $V_R = V_{RRM}$	$T_J = 25^\circ\text{C}$	MAX.	5	μA
		$T_J = 125^\circ\text{C}$		3	mA

Note 1: Minimum I_{GT} is guaranteed at 5% of I_{GT} max.

Note 2: For both polarities of A2 referenced to A1.

THERMAL RESISTANCE				
SYMBOL				UNIT
$R_{th(j-c)}$	Junction to case (AC)	TO-3P	0.6	$^\circ\text{C/W}$
		TO-263/TO-220AB	0.8	
		TO-3P Insulated	0.9	
		TO-220AB Insulated	1.7	
$R_{th(j-a)}$	Junction to ambient	$S = 1\text{ cm}^2$ TO-263	45	
		TO-220AB Insulated, TO-220AB	60	
		TO-3P, TO-3P Insulated	50	

S = Copper surface under tab.

PRODUCT SELECTOR

PART NUMBER	VOLTAGE (xx)				SENSITIVITY	TYPE	PACKAGE
	600 V	800 V	1000 V	1200 V			
26TxxA-B/26TxxAI-B	V	V	V	V	50 mA	Standard	TO-220AB
26TxxA-CW/26TxxAI-CW	V	V	V	V	35 mA	Snubberless	TO-220AB
26TxxA-BW/26TxxAI-BW	V	V	V	V	50 mA	Snubberless	TO-220AB
26TxxB-B/26TxxBI-B	V	V	V	V	50 mA	Standard	TO-3P
26TxxB-CW/26TxxBI-CW	V	V	V	V	35 mA	Snubberless	TO-3P
26TxxB-BW/26TxxBI-BW	V	V	V	V	50 mA	Snubberless	TO-3P
26TxxH-B	V	V	V	V	50 mA	Standard	D ² PAK
26TxxH-CW	V	V	V	V	35 mA	Snubberless	D ² PAK
26TxxH-BW	V	V	V	V	50 mA	Snubberless	D ² PAK

AI: Insulated TO-220AB package

BI: Insulated TO-3P package

ORDERING INFORMATION

ORDERING TYPE	MARKING	PACKAGE	WEIGHT	BASE Q'TY	DELIVERY MODE
26TxxA-yy	26TxxA-yy	TO-220AB	2.0g	50	Tube
26TxxAI-yy	26TxxAI-yy	TO-220AB (insulated)	2.3g	50	Tube
26TxxB-yy	26TxxB-yy	TO-3P	4.3g	30	Tube
26TxxBI-yy	26TxxBI-yy	TO-3P (insulated)	4.8g	30	Tube
26TxxH-yy	26TxxH-yy	D ² PAK	2.0g	50	Tube

Note: xx = voltage, yy = sensitivity

ORDERING INFORMATION SCHEME

		26	T	06	A - BW
Current					
26 = 25A					
Triac series					
Voltage					
06 = 600V					
08 = 800V					
10 = 1000V					
12 = 1200V					
Package type					
A = TO-220AB (non-insulated)					
AI = TO-220AB (insulated)					
B = TO-3P (non-insulated)					
BI = TO-3P (insulated)					
H = TO-263 (D ² PAK)					
IGT Sensitivity					
BW = 50mA Snubberless					
CW = 35mA Snubberless					
B = 50mA Standard					

Fig.1 Maximum power dissipation versus RMS on-state current (full cycle)

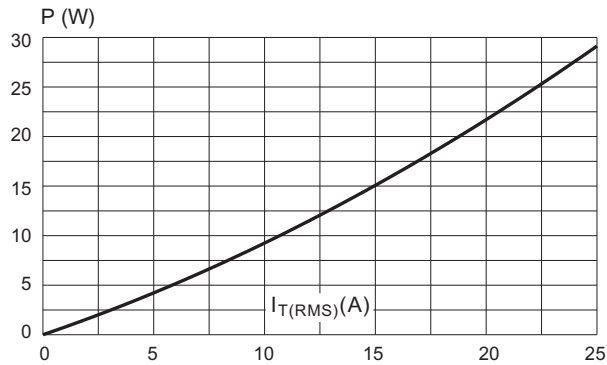


Fig.2 RMS on-state current versus case temperature (full cycle)

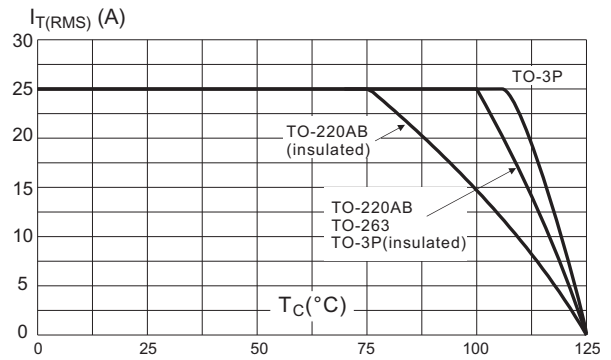


Fig.3 D²PAK RMS on-state current versus ambient temperature (printed circuit board FR4, copper thickness: 35μm)(full cycle)

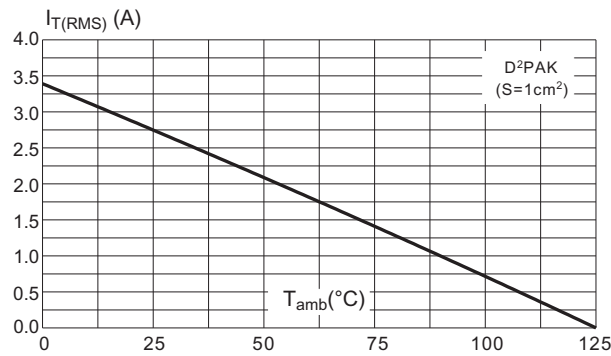


Fig.4 Relative variation of thermal impedance versus pulse duration.

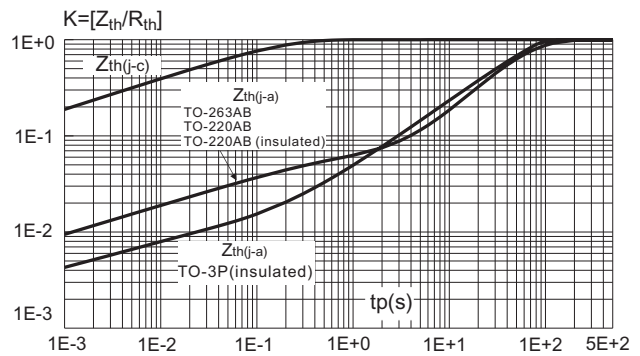


Fig.5 On-state characteristics (maximum values).

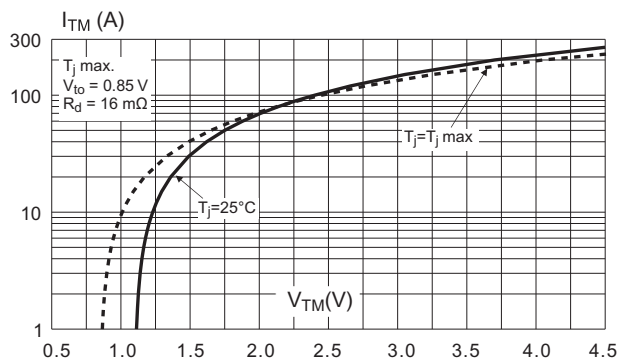


Fig.6 Surge peak on-state current versus number of cycles.

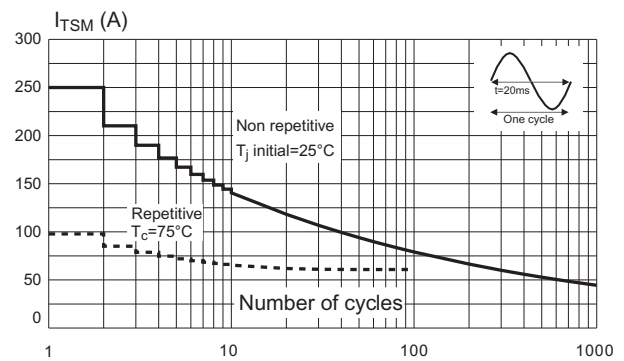


Fig.7 Non-repetitive surge peak on-state current for a sinusoidal pulse with width $t_p < 10\text{ms}$. and corresponding value of I^2t .

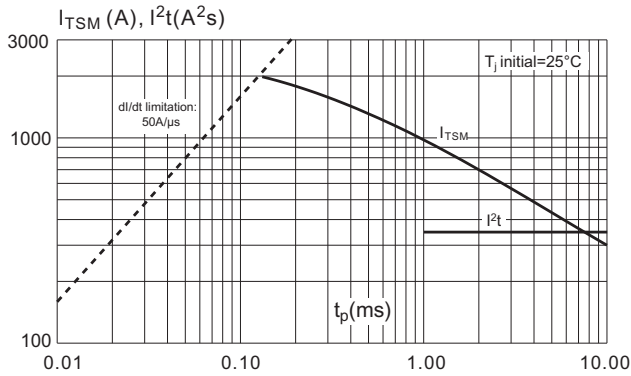


Fig.8 Relative variation of gate trigger current, holding current and latching current versus junction temperature (typical values).

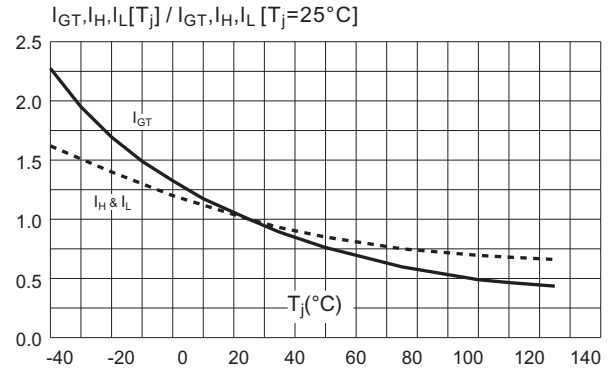


Fig.9 Relative variation of critical rate of decrease of main current versus $(dV/dt)_c$ (typical values).

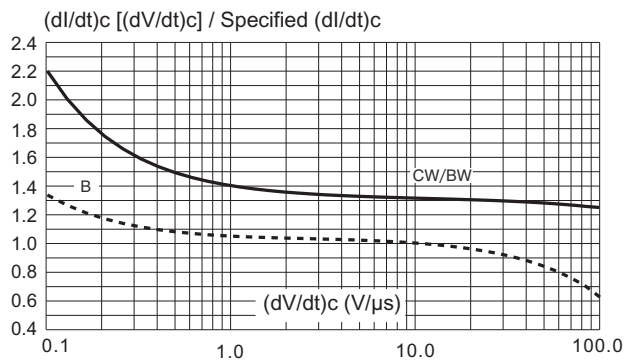


Fig.10 Relative variation of critical rate of decrease of main current versus T_j

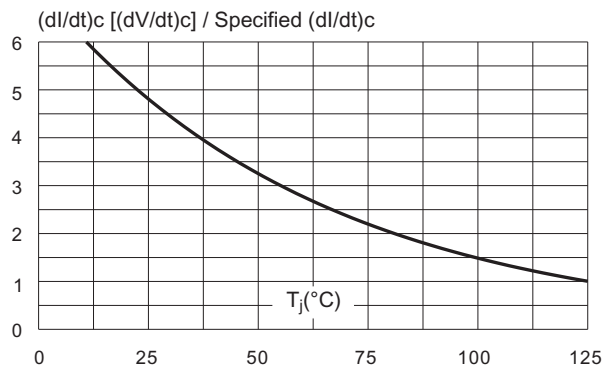
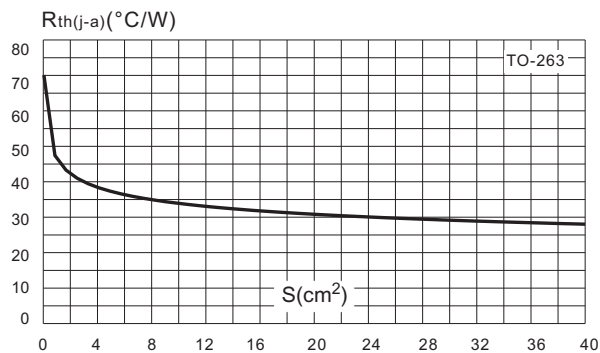
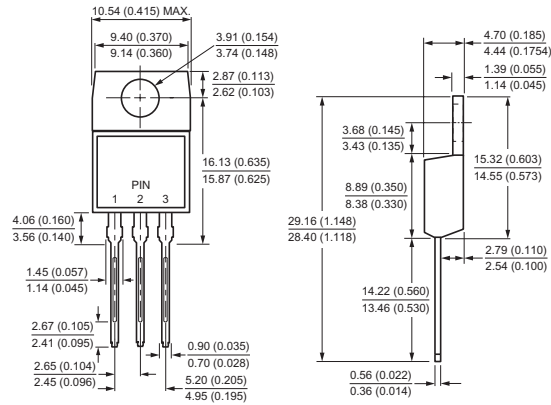


Fig.11 D²PAK thermal resistance junction to ambient versus copper surface under tab (printed circuit board FR4, copper thickness: 35μm)

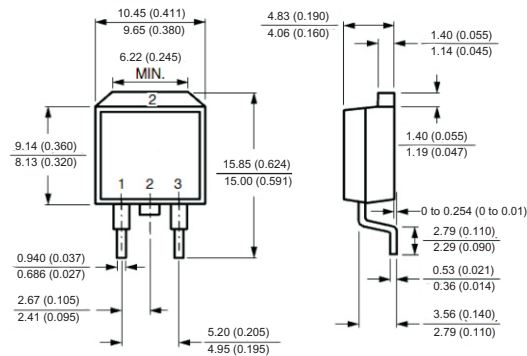


Case Style

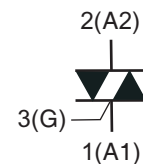
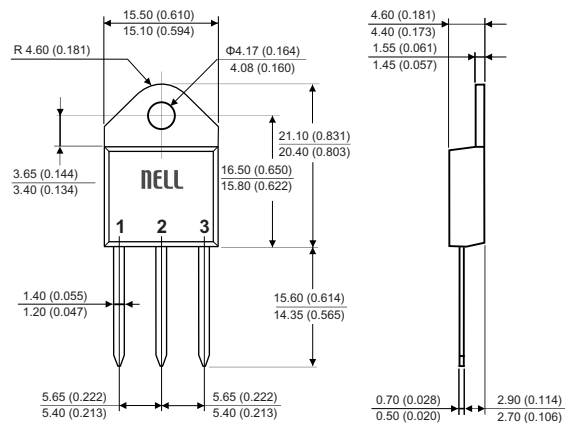
TO-220AB



TO-263(D²PAK)



TO-3P



All dimensions in millimeters(inches)